

Notice of Allowability	Application No.	Applicant(s)	
	09/679,042	DALAL ET AL.	
	Examiner Mujtaba K Chaudry	Art Unit 2133	

-- The MAILING DATE of this communication appears on the cover sheet with the correspondence address--

All claims being allowable, PROSECUTION ON THE MERITS IS (OR REMAINS) CLOSED in this application. If not included herewith (or previously mailed), a Notice of Allowance (PTOL-85) or other appropriate communication will be mailed in due course. THIS NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RIGHTS. This application is subject to withdrawal from issue at the initiative of the Office or upon petition by the applicant. See 37 CFR 1.313 and MPEP 1308.

1. This communication is responsive to 05/20/2004.
2. The allowed claim(s) is/are 1-7.
3. The drawings filed on _____ are accepted by the Examiner.
4. Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).
 - a) All
 - b) Some* c) None of the:
 1. Certified copies of the priority documents have been received.
 2. Certified copies of the priority documents have been received in Application No. _____.
 3. Copies of the certified copies of the priority documents have been received in this national stage application from the International Bureau (PCT Rule 17.2(a)).

* Certified copies not received: _____.

Applicant has THREE MONTHS FROM THE "MAILING DATE" of this communication to file a reply complying with the requirements noted below. Failure to timely comply will result in ABANDONMENT of this application.
THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.

5. A SUBSTITUTE OATH OR DECLARATION must be submitted. Note the attached EXAMINER'S AMENDMENT or NOTICE OF INFORMAL PATENT APPLICATION (PTO-152) which gives reason(s) why the oath or declaration is deficient.
6. CORRECTED DRAWINGS (as "replacement sheets") must be submitted.
 - (a) including changes required by the Notice of Draftsperson's Patent Drawing Review (PTO-948) attached
 - 1) hereto or 2) to Paper No./Mail Date 01/28/2004.
 - (b) including changes required by the attached Examiner's Amendment / Comment or in the Office action of Paper No./Mail Date _____.
7. DEPOSIT OF and/or INFORMATION about the deposit of BIOLOGICAL MATERIAL must be submitted. Note the attached Examiner's comment regarding REQUIREMENT FOR THE DEPOSIT OF BIOLOGICAL MATERIAL.

Attachment(s)

1. Notice of References Cited (PTO-892)
2. Notice of Draftperson's Patent Drawing Review (PTO-948)
3. Information Disclosure Statements (PTO-1449 or PTO/SB/08),
Paper No./Mail Date _____
4. Examiner's Comment Regarding Requirement for Deposit
of Biological Material
5. Notice of Informal Patent Application (PTO-152)
6. Interview Summary (PTO-413),
Paper No./Mail Date _____
7. Examiner's Amendment/Comment
8. Examiner's Statement of Reasons for Allowance
9. Other _____

ALBERT DECADY
SEARCHER/PATENT EXAMINER
ART UNIT 2100
APR 2004

REASONS FOR ALLOWANCE

Claims 1-7 are allowed. The following is an Examiner's statement of reasons for allowance:

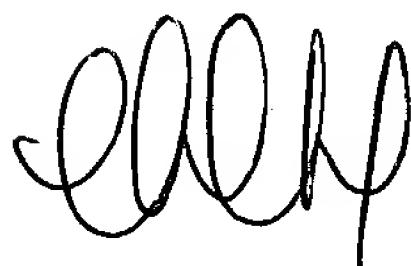
Independent claims 1 of the present application teaches an apparatus for testing an integrated circuit comprising a data source coupled to the integrated circuit to provide test signals to the integrated circuit; a plurality of relays selectively coupling the integrated circuit to the apparatus wherein the integrated circuit is tested; a plurality of fan out elements coupled to receive data pulses from the plurality of relays and to distribute the data pluses to a plurality of latches; and a strobe element associated with each of the plurality of latches to transfer the data pluses from the input port to an output port of each of the plurality of latches. The foregoing limitations are not taught nor fairly suggested from the prior arts of record. The prior art of record, namely Turnquist et al., basically teaches an event-based test system is configured to test an electronics device under test (DUT) by supplying a test signal to the DUT and evaluating an output of the DUT at a timing of a strobe signal. The event based test system includes an event memory for storing timing data of each event formed with an integer multiple of a reference clock period and a fraction of the reference clock period wherein the timing data represents a time difference between a current event and a reference point, an address sequencer for generating address data for accessing the event memory, a timing count and scaling logic for generating an event start signal, an event generation unit for generating each event based on the event start signal and data indicating the fraction of the reference clock period, and a host computer for controlling an overall operation of the event based test system. In particular, the prior art does not teach nor fairly suggest *a plurality of relays selectively coupling the integrated*

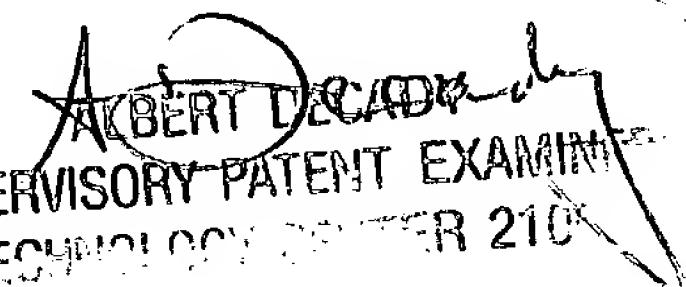
circuit to the apparatus wherein the integrated circuit is tested; a plurality of fan out elements coupled to receive data pulses from the plurality of relays and to distribute the data pluses to a plurality of latches. Emphasis added. Therefore, it is the Examiner's conclusion that the claims in the present application are allowable over the prior arts of record. Furthermore, independent claim 4 includes similar limitations to those found in claim 1 and therefore is allowable as well. Dependent claims 2-3 and 5-7 inherently include limitations of independent claims 1 and 4 and therefore are allowable as well.

Any inquiries concerning this communication should be directed to the examiner, Mujtaba Chaudry who may be reached at 703-305-7755. The examiner may normally be reached Mon – Thur 7:30 am to 4:30 pm and every other Fri 8:00 am to 4:00 pm.

If attempts to reach the examiner by telephone are unsuccessful, please contact the examiner's supervisor, Albert DeCady at 703-305-9595. The fax phone number for the organization where this application is assigned is 703-746-7239.

Any inquiry of general nature or relating to the status of this application or proceeding should be directed to the receptionist at 703-305-3900.


Mujtaba Chaudry
Art Unit 2133
August 18, 2004


ALBERT DECADY
SUPERVISORY PATENT EXAMINER
TECHNOLOGY CENTER 2100

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